Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,013	SCHMIDT ET AL.	
Examiner	Art Unit	
Chun-Kuan (Mike) Lee	2181	

	SEAR	CHED	
Class	Subclass	Date	Examiner
710	29	1/22/2007	CHUN- KUAN Lee
710	52-23	1/22/2007	
710	55	1/22/2007	
710	60	1/22/2007	1
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	<u> </u>				

(INCLUDING SEARCH	STRATEGY	<u>')</u>
	DATE	EXMR
(EAST) US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	1/22/2007	CHUN- KUAN Lie.
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